

## **Quarterly Reliability Monitoring Results**

## Quarters: Q3/2021 to Q4/2022

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number						
		PZU6.8B1A-Q						
		Part Description						
		Nexperia DHAM						
		SMD package						
		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
	<b>TEST</b> Pre- and Post-Stress							
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
# A1	<b>PC</b> Preconditioning	JESD22-A113 Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85% Reflow soldering	24 hours 168 hours 3 cycles	1168	66640	0		
# B1	HTRB	MIL-STD-750-1 M1038 Method A Tj = Tjmax, VR = 80 % of rated reverse voltage	1000 hours	198	11960	0		
# B1b	SSOP Steady State Operational	MIL-STD-750-1 M1038 Method B Tj = Tjmax, Iz = 100% of max. datasheet reverse current	1000 hours	24	1760	0		
# A4	TC Temperature Cycling	JESD22-A104 -65 °C to Tjmax, not to exceed 150°C	1000 cycles	240	14800	0		
# A3 <b>or</b>	UHAST Unbiased HAST	JESD22-A118 Tamb = 130 °C, RH = 85 % JESD22-A102 Tamb = 121 °C, RH = 100 %	—96 hours	240	14800	0		
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)						
# A2 - It	H3TRB High Humidity High	JESD22-A101 Tamb = 85 °C, RH = 85%, VR = 80 % of	1000 have	240	14000	0		
# A2 alt	Temperature Reverse Bias	MIL-STD-750 Method 1037 ton = toff, devices powered to insure ΔTj =	1000 hours	240	14800	0		
# A5	Intermittent Operating Life	, .	1000 hours	264	16720	0		
# C8	<b>RSH</b> Resistance to Solder Heat	JESD22-A111 260 °C ± 5 °C	10 s	184	5520	0		
# C10	<b>SD</b> Solderability	J-STD-002		501	5010	0		

<sup>[1]</sup> The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Zener	11960	0	0,36	2,82E+09

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